## THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/809,322

Confirmation No.:

8225

Applicant

: Yoji HATA, et al. : March 26, 2004

Filed TC/A.U.

: 2812

Examiner

: To Be Assigned : 037133.53131US

Docket No. Customer No.

: 23911

Title

: Lsi Inspection Method and Defect Inspection Data Analysis

**Apparatus** 

## CLAIM OF PRIORITY UNDER 35 U.S.C. § 119

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The benefit of the filing date of prior Japanese application No. 2003-106271, filed in Japan on April 10, 2003, is hereby requested and the right of priority under 35 U.S.C. § 119 is hereby claimed.

In support of this claim, filed herewith is a certified copy of the original Japanese application.

Respectfully submitted

Herbert I. Cantor

Registration No. 24,392

July 15, 2004

CROWELL & MORING LLP Intellectual Property Group P.O. Box 14300

Washington, DC 20044-4300 Telephone No.: (202) 624-2500 Facsimile No.: (202) 628-8844